

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Attorney Docket No.: Divisional of Applic. No. PEK-In1163 D 10/200,934 Applicant Wilhelm Asam et al. Filing Date of Divisional Group Art Unit January 2, 2004 2826
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EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>Sm</i>	A	5,309,090	05/94	Lipp	324	158.1	
<i>Sm</i>	B	5,751,015	05/98	Corbett et al.	257	48	
<i>Sm</i>	C	5,436,494	07/95	Moslehi	257	467	
<i>Sm</i>	D	5,406,212	04/95	Hashinaga et al.	324	760	
<i>Sm</i>	E	4,356,379	10/82	Graeme	219	209	
<i>Sm</i>	F	5,414,370	05/95	Hashinaga et al.	324	760	
<i>Sm</i>	G	5,195,827	03/93	Audy et al.	374	172	
<i>Sm</i>	H	5,280,327	01/94	Buks	396	389	
	I						

FOREIGN PATENT DOCUMENT

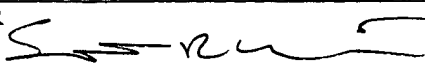
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J						
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>Sm</i>		Meijer, G.: "Thermal Sensor Based on Transistors", Elsevier Sequoia, 1986, pp. 103-125.
<i>Sm</i>		Shideler, J. et al.: "A Systematic Approach to Wafer Level Reliability", Solid State Technology, March 1995, pp. 47, 48, 50, 52, 54.

EXAMINER <i>Sm</i>	DATE CONSIDERED 6-14-2004
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sw		Anonymous: "Method to Determine Substrate Potential and Chip Temperature", Research Disclosure, March 1990, No. 311, New York, XP-000104454.					
Sw		R.A. Bianchi et al.: "CMOS-Compatible Temperature Sensor with Digital Output for Wide Temperature Range Applications", Microelectronics Journal, No. 31, 2000, pp. 803-810.					
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